

<b>Notice of References Cited</b>		Application/Control No. 10/566,621	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
		Examiner RONG LE	Art Unit 2423	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,125,259	09-2000	Perlman, William	725/28
*	B US-2002/0158779	10-2002	Ouyang, Yen-I	341/28
*	C US-7,061,477	06-2006	Noguchi, Kunihiko	345/204
*	D US-6,301,230	10-2001	Ito et al.	370/313
*	E US-2002/0162112	10-2002	Javed, Shoeb M.	725/87
*	F US-6,181,364	01-2001	Ford, K. Harlan	725/32
*	G US-6,940,502	09-2005	Lin et al.	345/211
*	H US-2004/0036622	02-2004	Dukach et al.	340/691.6
*	I US-6,272,318	08-2001	Yoshioka, Kenji	340/7.28
*	J US-2003/0063691	04-2003	Shiozawa et al.	375/340
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

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